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Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/057,179	MA ET AL.	
Examiner	Art Unit	
Jason M. Perilla	2638	

SEARCHED			
Class	Subclass	Date	Examiner
375	229-236	6/30/2005	JP
	316	6/30/2005	JP
	346	6/30/2005	JP
	348	6/30/2005	JP
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	6/30/2005	JP
Inventor Name Search	6/30/2005	JP
IEEE Iterative AND channel AND estimate	6/30/2005	JP